



DEFENSE LOGISTICS AGENCY  
LAND AND MARITIME  
POST OFFICE BOX 3990  
COLUMBUS, OH 43218-3990

June 24, 2015

Alex Chang  
President  
Golden Altos Corporation  
402 South Hillview Drive  
Milpitas, CA 95035-5464

Dear Mr. Chang:

Re: Commercial Laboratory Suitability Status; MIL-STD-883; FSC 5962; VQC-15-029220; McNulty. CN: 045878.

Based on the results of the DLA Land and Maritime audit conducted during the week of November 18-20, 2014, Golden Altos Corporation is considered suitably equipped to perform the MIL-STD-883 tests, listed in the enclosure, on monolithic microcircuits in accordance with the requirements of military specification MIL-PRF-38535 effective immediately.

Your laboratory is to maintain a record for all microcircuit testing and submit a summary annually to DLA Land and Maritime-VQC which will include the following as a minimum:

1. Retention Report
  - a. Military Part Number
  - b. Vendor Part Number
  - c. Manufacturer/ Customer
  - d. Lot Date Code
  - e. Test Method(s) and Specified Conditions
  - f. Date Test Completed
  - g. Quantity Tested
  - h. Quantity Accepted and Rejected When Evaluating Acceptability
2. Summary of Internal Audit Results
3. Master List of Controlled Documents, Including Revision Information

The standard retention reporting period is from 01 Jan through 31 Dec. Your report is then due by 01 March the following year.

Test labs shall notify the qualifying activity immediately after learning of a potential issuance of a GIDEP alert, problem advisory or major quality/reliability problem on their military products utilizing the test methods on the attached enclosure. Failure to provide prior notification may be grounds for removal from DLA Land and Maritime's Commercial Lab Suitability Listing.

This Laboratory Suitability is subject to the policies, procedures, and conditions of the Defense Standardization Program, as published in the manual DoD 4120.24-M, SD-6, and the DLA Land and Maritime-VQ Laboratory Suitability Booklet.

This laboratory suitability is valid until withdrawn by DLA Land and Maritime-VQC. Any deviation to the test method or condition(s) listed herein must be approved by the Qualifying Activity.

If you have any questions, please contact Mr. Sean McNulty at (614) 692-8800.

Sincerely,

MICHAEL S. ADAMS  
Chief  
Custom Devices Branch

Enclosure

Visit us on the web at: [http://www.landandmaritime.dla.mil/offices/sourcing\\_and\\_qualification/](http://www.landandmaritime.dla.mil/offices/sourcing_and_qualification/)

Enclosure to DLA Land and Maritime-VQ (VQC-15-029220)

<b><u>TEST</u></b>	<b><u>METHOD/CONDITION</u></b>	<b><u>Performed at Golden Altos Corporation</u></b>	<b><u>Other Labs (subcontractors)</u></b>
Moisture Resistance	1004	x	
Steady State Life Test	1005 A,B,C,D	x	
Stabilization Bake	1008 A,B,C,D,E,F,G	x	
Salt Atmosphere	1009 A	x	
Temperature Cycling	1010 A,B,C,D,E,F	x	
Thermal Shock	1011 A,B,C		E.A.S.T. EAG (Backup)
Seal	1014 A1,A2,C <sub>1</sub>	x	
Burn-in	1015 A,B,C,D	x	Integra Tech (Backup) ICE (Backup)
Internal Water-Vapor Content	1018		Atlantic Analytical Pernika (Backup)
Constant Acceleration	2001 D,E	x	
Mechanical Shock	2002 B	x	Quanta Labs (Backup)
Solderability	2003 A,B	x	
Solderability	2003 A,B,C,S,CGA 2.3.2		Six Sigma
Lead Integrity	2004 B1,B2,D	x	
Vibration, Variable Frequency	2007 A	x	Hi-Reliability Microelectronics (Backup)
External Visual	2009	x	
Internal Visual	2010 A,B	x	
Destructive Bond Strength	2011 D	x	
Radiography	2012 (Film)		NDT Labs ECR Labs (Backup)
Internal Visual and Mechanical	2014	x	
Resistance to Solvents	2015	x	
Physical Dimensions	2016	x	
Die Shear Strength	2019	x	

<b>PIND</b>	<b>2020 A,B</b>	<b>x</b>	<b>NDT Labs ECR Labs</b>
<b>Non-Destructive Bond Pull</b>	<b>2023</b>	<b>x</b>	
<b>Lid Torque</b>	<b>2024</b>	<b>x</b>	
<b>Adhesion of Lead Finish</b>	<b>2025</b>	<b>x</b>	
<b>Substrate attach Strength</b>	<b>2027</b>	<b>x</b>	
<b>PGA Destructive Lead Pull</b>	<b>2028</b>		<b>Hi-Reliability Microelectronics</b>
<b>ESDS Classification</b>	<b>3015</b>		<b>ICE</b>
<b>Electrical Test</b>	<b>Note 1</b>		<b>Hi-Reliability Microelectronics</b>
<b>Moisture Resistance</b>	<b>1004</b>	<b>x</b>	
<b>Steady State Life Test</b>	<b>1005 A,B,C,D</b>	<b>x</b>	
<b>Stabilization Bake</b>	<b>1008 A,B,C,D,E,F,G</b>	<b>x</b>	
<b>Salt Atmosphere</b>	<b>1009 A</b>	<b>x</b>	
<b>Temperature Cycling</b>	<b>1010 A,B,C,D,E,F</b>	<b>x</b>	
<b>Thermal Shock</b>	<b>1011 A,B,C</b>		<b>E.A.S.T. EAG (Backup)</b>

**Note 1:** Hi-Reliability Microelectronics electrical test systems are certified in compliance with MIL-STD-883 paragraph 4.5 as applicable. Hi-Reliability Microelectronics system is suitable to perform electrical test over military case temperature ( $T_{case}$ ) of 25°, 125°, and -55° C. Electrical Test suitability does not cover individual test programs. It is the responsibility of the commercial lab to obtain a record of customer approval stating that the hardware/software integration, including resolution and accuracy are adequate to meet the forcing and measurement conditions required, for the specified device type.